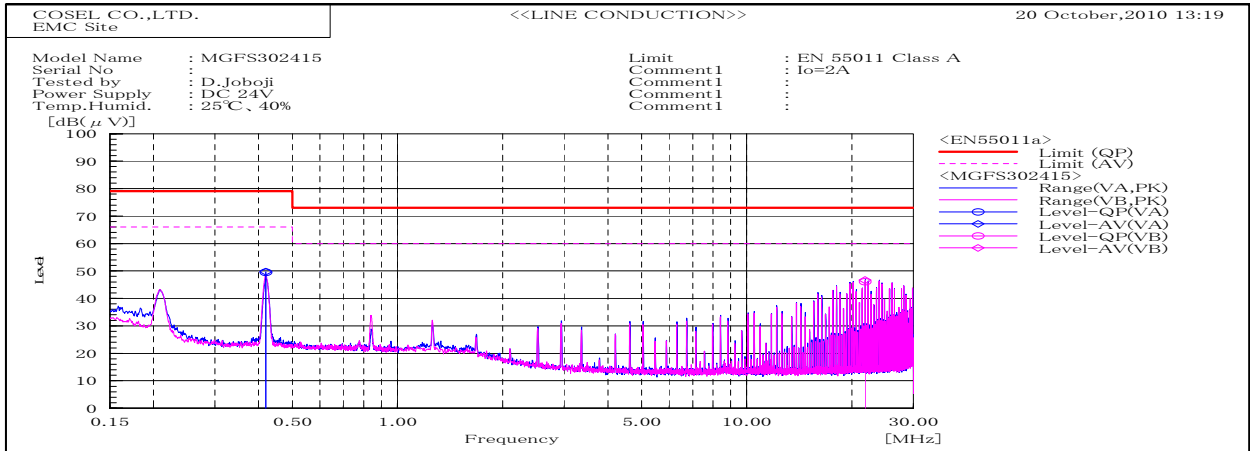
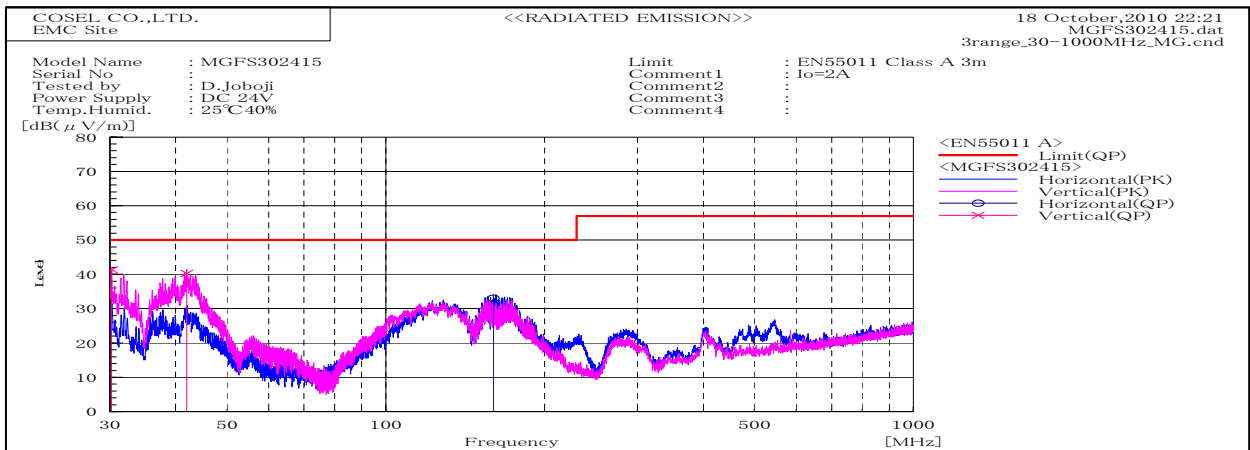


DATA SHEET			Date	20-Oct-10
Model	MGFS302415		Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission		Humid.	40 %RH
			Tested by	D.Joboji



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.42002		VA	39.4	39.6	10.1	49.5	49.7	79	66	29.5	16.3	Pass	
21.83275		VB	35.1	35.7	11	46.1	46.7	73	60	26.9	13.3	Pass	

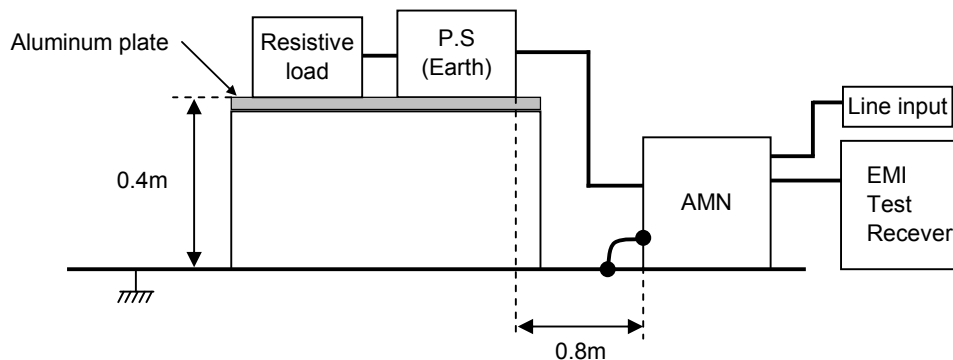


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
30.218	V	Stable	54.9	-13.5		41.4		50	8.6	Pass	101	339
41.971	V	Stable	59.8	-19.6		40.2		50	9.8	Pass	104	111
159.926	H	Stable	53.8	-20.8		33		50	17	Pass	148	178

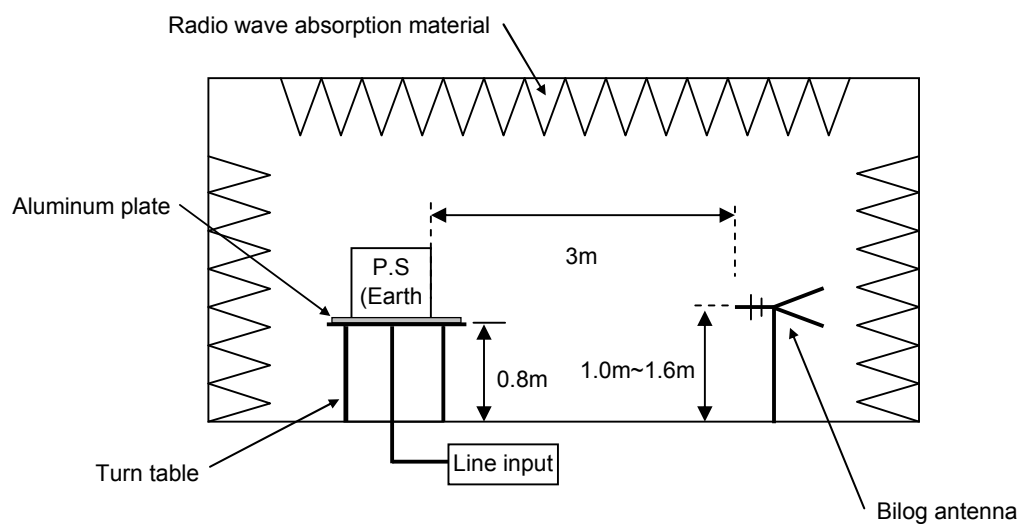
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name : MGFS3024□□/MGFW3024□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

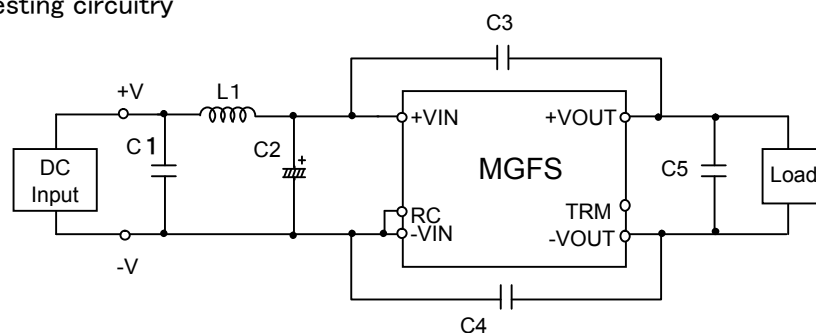


Fig.1 Testing circuitry 1

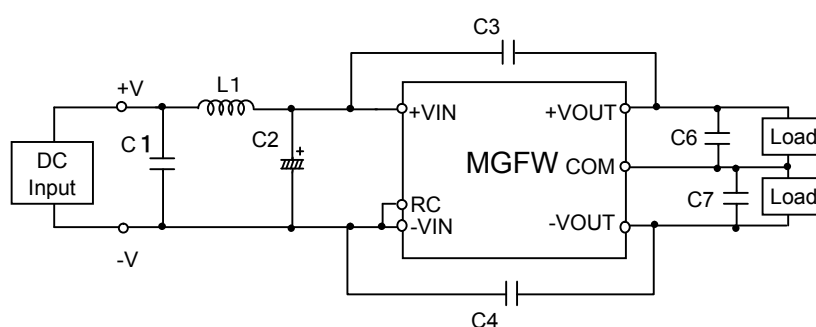


Fig.2 Testing circuitry 2

L1	: 0.6uH	CI8C-0R6	(KORIN ELECTRONICS)
C1	: 50V 4.7 μ F	Ceramic Capacitor	
C2	: 50V 100 μ F	Electrolytic Capacitor	
C3,C4	: 2kV 1000pF	Ceramic Capacitor	
C5,C6,C7	: 25V 22 μ F	Ceramic Capacitor	